10/666,553

1. (CURRENTLY AMENDED) A non-contact tester for electronic circuits, comprising in combination:

an electronic circuit which includes at least one a plurality of wireless i/o cells and means for sending and receiving signals via each of the at least one wireless i/o cells, and a wireless i/o cell being provided for each contact point on the electronic circuit to be tested; and

40

an independent scanning head having at least one a plurality of wireless i/o cells compatible with the at least one wireless i/o cells on the electronic circuit, such that data may be exchanged with the electronic circuit to confirm proper functioning of the electronic circuit, and the number of wireless i/o cells on the independent scanning head corresponding in a one to one relationship with the number of wireless i/o cells on the electronic circuit being tested.

- 2. (CANCELED)
- 3. (CANCELED)
- 4. (CURRENTLY AMENDED) The non-contact tester for electronic circuits as defined in claim 1, wherein the means for sending and receiving signals via <u>each of</u> the <u>at least one</u> wireless i/o cells is a radio frequency interface.
- 5. (PREVIOUSLY PRESENTED) The non-contact tester for electronic circuits as defined in claim 4, wherein the radio frequency interface includes at least one transmitter and at least one receiver.
- 6. (CURRENTLY AMENDED) The non-contact tester for electronic circuits as defined in claim 1, wherein the means for sending and receiving signals via <u>each of</u> the <u>at least one</u> wireless i/o cells is an optical interface.
- 7. (PREVIOUSLY PRESENTED) The non-contact tester for electronic circuits as defined in claim 6, the optical interface includes at least one light emitter and at least one light receptor.
- 8. (CURRENTLY AMENDED) The non-contact tester for electronic circuits as defined in claim 1, wherein the means for sending and receiving signals via <u>each of</u> the <u>at least one</u> wireless i/o cells is a magnetic interface.
- (PREVIOUSLY PRESENTED) The non-contact tester for electronic circuits as defined in claim 8, wherein the magnetic interface includes a magnetic detector and a magnetic generator.

10/666,553

10. (WITHDRAWN) A method of testing for electronic circuits, comprising the steps of:

providing a non-contact tester having an electronic circuit which includes at least one wireless i/o cell and means for sending and receiving signals via the at least one wireless i/o cell;

providing an independent scanning head having at least one wireless i/o cell compatible with the at least one wireless i/o cell on the electronic circuit, such that data may be exchanged with the electronic circuit to confirm proper functioning of the electronic circuit; and

testing the electronic circuit to confirm proper functioning of the electric circuit.

- 11. (WITHDRAWN) The method as defined in claim 10, wherein the means for sending and receiving signals via the at least one wireless i/o cell is a radio frequency interface.
- 12. (WITHDRAWN) The method as defined in claim 11, wherein the radio frequency interface includes at least one transmitter and at least one receiver.
- 13. (WITHDRAWN) The method as defined in claim 10, wherein the means for sending and receiving signals via the at least one wireless i/o cell is an optical interface.
- 14. (WITHDRAWN) The method as defined in claim 13, the optical interface includes at least one light emitter and at least one light receptor.
- 15. (WITHDRAWN) The method as defined in claim 10, wherein the means for sending and receiving signals via the at least one wireless i/o cell is a magnetic interface.
- 16. (WITHDRAWN) The method defined in claim 15, wherein the magnetic interface includes a magnetic detector and a magnetic generator.